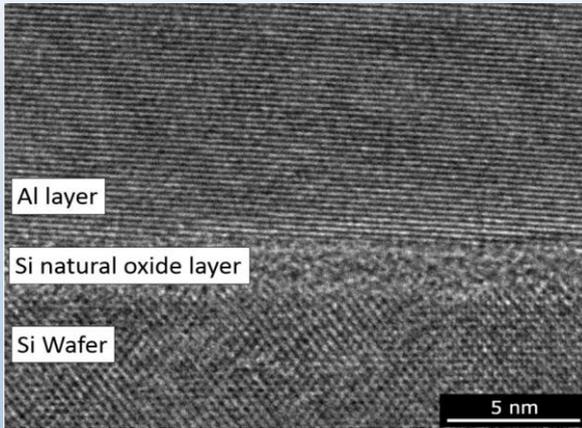
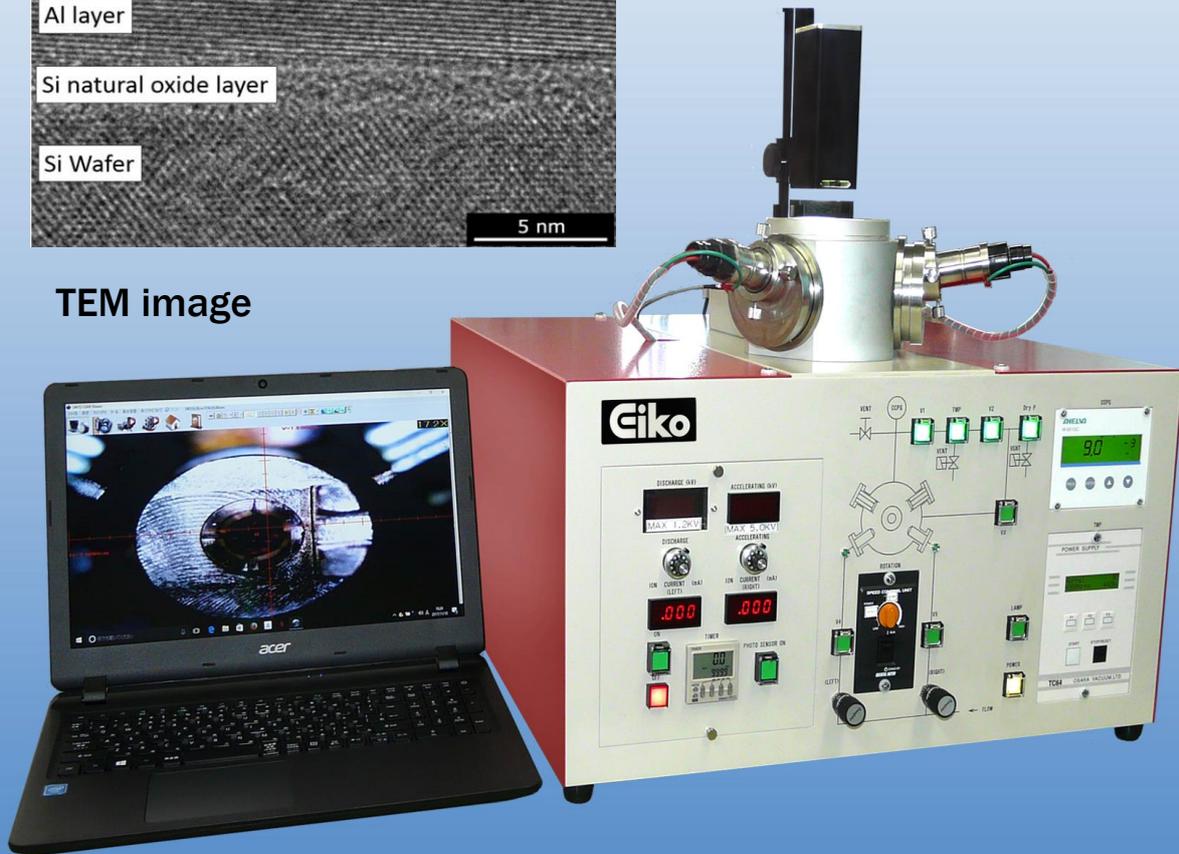


Ion Milling System

IE-30



TEM image



■ General

- Apply argon gas to a sample to scrape the surface of the sample. And this system can prepare a sample of observation for TEM.

■ Feature

- The incidence angle of ion beam can be changed between 0° and 10°.
- The image of the CCD camera can be displayed on a PC. Therefore it is easy to confirm sample.

■ Specifications

1. Ion source: Penning ion source × 2
2. Accelerating voltage: 0 to 5kV
3. Milling angle: $\pm 10^\circ$
4. Sample size: 3mm in diameter
5. Sample rotation: 1 to 6 rpm
6. Ultimate pressure: 6.5×10^{-4} Pa
7. Dimensions: 610(W) × 620(D) × 655(H) mm
8. Weight: 80 kg (without PC and pump)
9. Input power: AC100V/10A